

**Search Notes**

Application/Control No.

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Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

FURUYA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
713	193	3/16/2006	ECT
380	210	3/16/2006	ECT
380	259	3/16/2006	ECT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search		3/16/2007	ECT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH, NPL	3/16/2006	ECT